

IRFS4127PbF IRFSL4127PbF

HEXFET® Power MOSFET

Applications

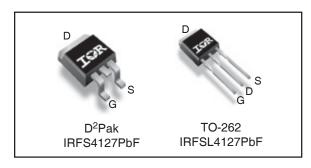
- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits

G

V _{DSS}		200V
R _{DS(on)}	typ.	18.6m Ω
	max.	22m Ω
I _D		72A

Benefits

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free



G	D	S
Gate	Drain	Source

Absolute Maximum Ratings

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V	72	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	51	Α
I _{DM}	Pulsed Drain Current ①	300	
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	375	W
	Linear Derating Factor	2.5	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
dv/dt	Peak Diode Recovery ③	57	V/ns
T_J	Operating Junction and	-55 to + 175	°C
T _{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300	
	(1.6mm from case)		
	Mounting torque, 6-32 or M3 screw	10lb·in (1.1N·m)	

Avalanche Characteristics

E _{AS (Thermally limited)}	Single Pulse Avalanche Energy ©	250	mJ
I _{AR}	Avalanche Current ①	See Fig. 14, 15, 22a, 22b,	Α
E _{AR}	Repetitive Avalanche Energy 4	1	mJ

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ® ®		0.4	°C/M
$R_{\theta JA}$	Junction-to-Ambient ⑦ ®		40	°C/W

Static @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	200			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.23		V/°C	Reference to 25°C, I _D = 5mA①
R _{DS(on)}	Static Drain-to-Source On-Resistance		18.6	22	mΩ	$V_{GS} = 10V, I_D = 44A \oplus$
$V_{GS(th)}$	Gate Threshold Voltage	3.0		5.0	٧	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
I _{DSS}	Drain-to-Source Leakage Current			20		$V_{DS} = 200V, V_{GS} = 0V$
				250	μA	$V_{DS} = 200V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100	nΛ	V _{GS} = 20V
	Gate-to-Source Reverse Leakage			-100	nA	V _{GS} = -20V
R _{G(int)}	Internal Gate Resistance		3.0		Ω	

Dynamic @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	79			S	$V_{DS} = 50V, I_D = 44A$
Q_g	Total Gate Charge		100	150		I _D = 44A
Q_{gs}	Gate-to-Source Charge		30		nC	$V_{DS} = 100V$
Q_{gd}	Gate-to-Drain ("Miller") Charge		31		IIC	V _{GS} = 10V ④
Q _{sync}	Total Gate Charge Sync. (Q _g - Q _{gd})		69			$I_D = 44A, V_{DS} = 0V, V_{GS} = 10V$
t _{d(on)}	Turn-On Delay Time		17			$V_{DD} = 130V$
t _r	Rise Time		18			I _D = 44A
$t_{d(off)}$	Turn-Off Delay Time		56		ns	$R_G = 2.7\Omega$
t _f	Fall Time		22			V _{GS} = 10V ⊕
C _{iss}	Input Capacitance		5380			$V_{GS} = 0V$
C _{oss}	Output Capacitance		410			$V_{DS} = 50V$
C _{rss}	Reverse Transfer Capacitance		86		pF	f = 1.0MHz (See Fig.5)
C _{oss} eff. (ER)	Effective Output Capacitance (Energy Related)®		360			$V_{GS} = 0V$, $V_{DS} = 0V$ to 160V $(See Fig.11)$
C _{oss} eff. (TR)	Effective Output Capacitance (Time Related)®		590			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 160V $

Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current			76		MOSFET symbol
	(Body Diode)				Α	showing the
I _{SM}	Pulsed Source Current			300	A	integral reverse
	(Body Diode) ①					p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	٧	$T_J = 25^{\circ}C, I_S = 44A, V_{GS} = 0V $ ④
t _{rr}	Reverse Recovery Time		136			$T_J = 25^{\circ}C$ $V_R = 100V$,
			139		ns	$T_{J} = 125^{\circ}C$ $I_{F} = 44A$
Q _{rr}	Reverse Recovery Charge		458		nC	$T_J = 25^{\circ}C$ di/dt = 100A/ μ s \oplus
			688		IIC	$T_J = 125^{\circ}C$
I _{RRM}	Reverse Recovery Current		8.3		Α	$T_J = 25^{\circ}C$
t _{on}	Forward Turn-On Time	Intrins	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by T_{Jmax} , starting T_J = 25°C, L = 0.26mH R_G = 25 Ω , I_{AS} = 44A, V_{GS} =10V. Part not recommended for use above this value .
- $\label{eq:loss_def} \mbox{ } \mbox{ } \mbox{I}_{SD} \leq 44A, \mbox{ } \mbox{di/dt} \leq 760A/\mu s, \mbox{ } \mbox{V}_{DD} \leq \mbox{V}_{(BR)DSS}, \mbox{ } \mbox{T}_{J} \leq 175^{\circ} \mbox{C}.$
- 4 Pulse width \leq 400 μ s; duty cycle \leq 2%.

- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- $\ensuremath{\$}\xspace$ R_θ is measured at T_J approximately $90^\circ C$
- $\ \, \mbox{\Large 9} \,\, R_{\theta JC} \, \mbox{value shown is at time zero}$

2 www.irf.com

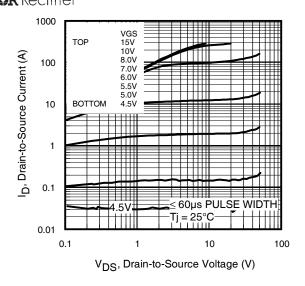


Fig 1. Typical Output Characteristics

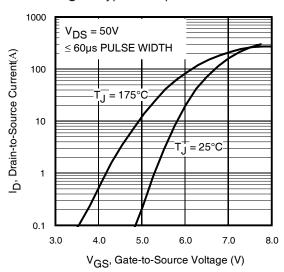


Fig 3. Typical Transfer Characteristics

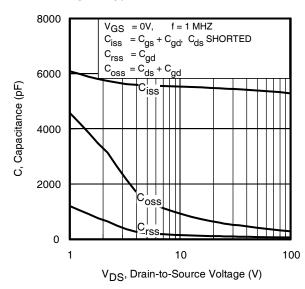


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage www.irf.com

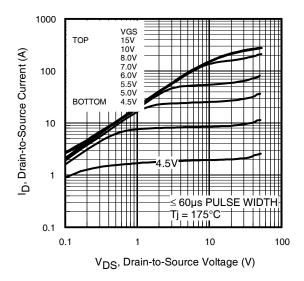


Fig 2. Typical Output Characteristics

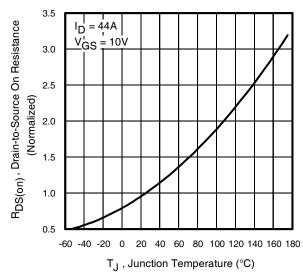


Fig 4. Normalized On-Resistance vs. Temperature

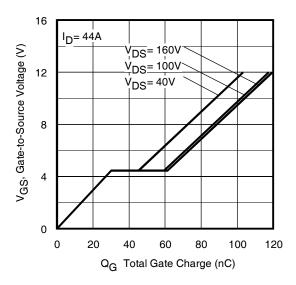


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

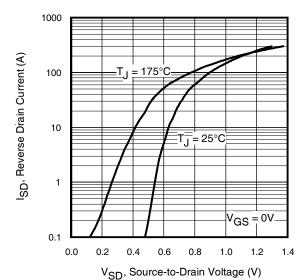
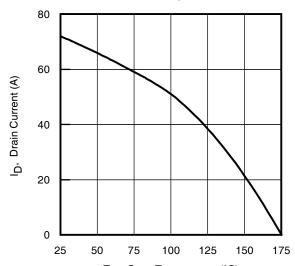


Fig 7. Typical Source-Drain Diode Forward Voltage



T_C , Case Temperature (°C) **Fig 9.** Maximum Drain Current vs.

Case Temperature

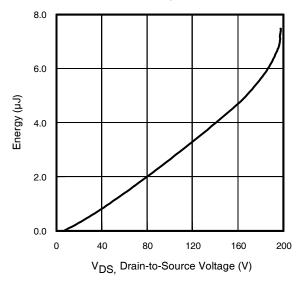


Fig 11. Typical C_{OSS} Stored Energy

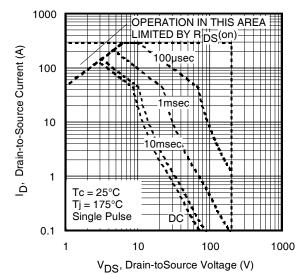


Fig 8. Maximum Safe Operating Area

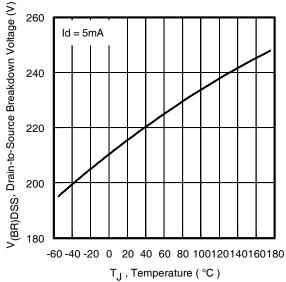


Fig 10. Drain-to-Source Breakdown Voltage

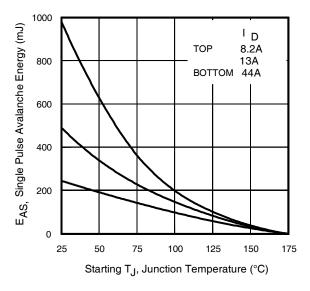


Fig 12. Maximum Avalanche Energy Vs. DrainCurrent www.irf.com

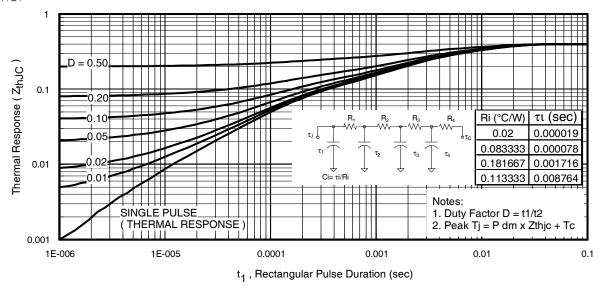


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

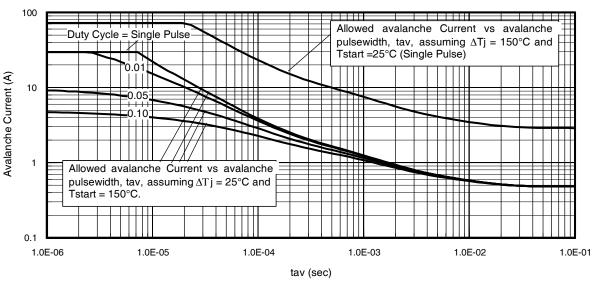


Fig 14. Typical Avalanche Current vs. Pulsewidth

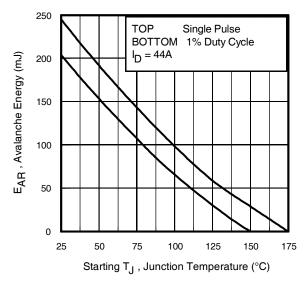


Fig 15. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption:
 - Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long asT_{imax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 16a, 16b.
- 4. $P_{D (ave)}$ = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 14, 15).

t_{av =} Average time in avalanche.

 $D = Duty cycle in avalanche = t_{av} \cdot f$

 $Z_{th,JC}(D, t_{av})$ = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \triangle T / \; Z_{thJC} \\ I_{av} &= 2\triangle T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$

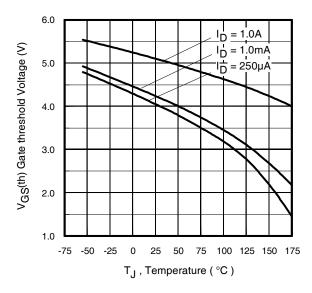


Fig 16. Threshold Voltage Vs. Temperature

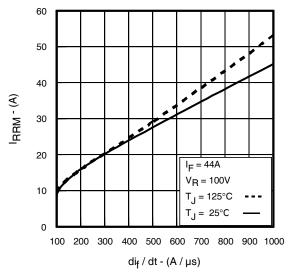


Fig. 18 - Typical Recovery Current vs. dif/dt

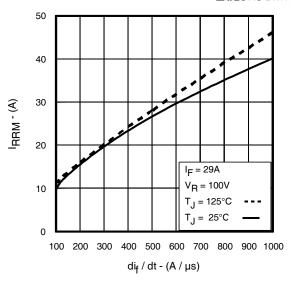


Fig. 17 - Typical Recovery Current vs. di_f/dt

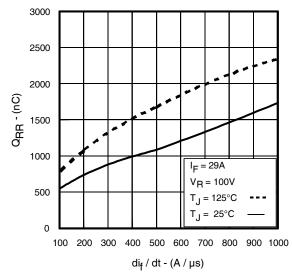


Fig. 19 - Typical Stored Charge vs. dif/dt

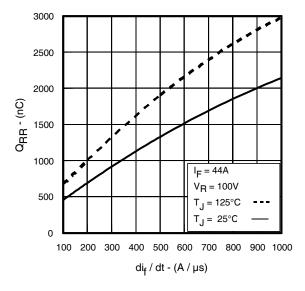


Fig. 20 - Typical Stored Charge vs. dif/dt

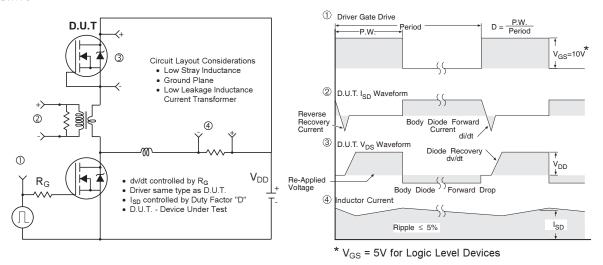


Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

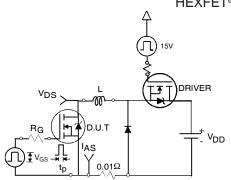


Fig 22a. Unclamped Inductive Test Circuit

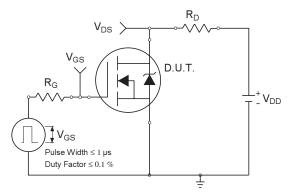


Fig 23a. Switching Time Test Circuit

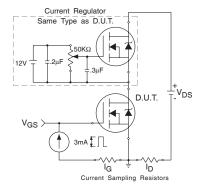


Fig 24a. Gate Charge Test Circuit www.irf.com

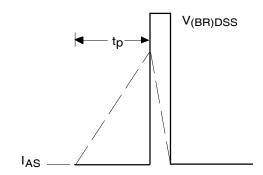


Fig 22b. Unclamped Inductive Waveforms

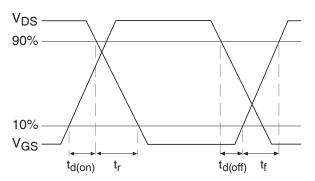


Fig 23b. Switching Time Waveforms

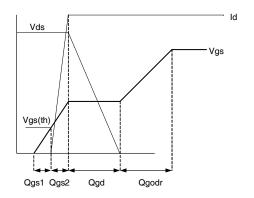
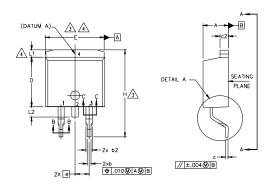


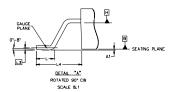
Fig 24b. Gate Charge Waveform

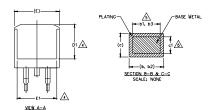
D²Pak (TO-263AB) Package Outline

Dimensions are shown in millimeters (inches)









NOTES

- 1, DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
- 4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
- 5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.
- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION; INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S			N			
M B O	MILLIM	ETERS	INC	INCHES		
L	MIN.	MAX.	MIN.	MAX.	O T E S	
Α	4.06	4.83	.160	.190		
A1	0.00	0.254	.000	.010		
b	0.51	0.99	.020	.039		
ь1	0.51	0.89	.020	.035	5	
b2	1,14	1.78	.045	.070		
b3	1,14	1.73	.045	.068	5	
С	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023	5	
c2	1,14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	-	.270		4	
E	9.65	10.67	.380	.420	3,4	
E1	6.22	_	.245		4	
e	2.54	BSC	.100	BSC		
Н	14.61	15.88	.575	.625		
L	1,78	2.79	.070	.110		
L1	-	1.65	-	.066	4	
L2	1.27	1.78	-	.070		
L3	0.25	BSC	.010 BSC			
L4	4.78	5.28	.188	.208		

LEAD ASSIGNMENTS

HEXFET

1.- GATE 2, 4.- DRAIN 3.- SOURCE

IGBTs, CoPACK

1.- GATE
2, 4.- COLLECTOR
3.- EMITTER

DIODES

1.- ANODE *
2. 4.- CATHODE
3.- ANODE

* PART DEPENDENT,

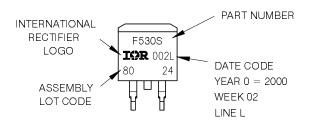
D²Pak (TO-263AB) Part Marking Information

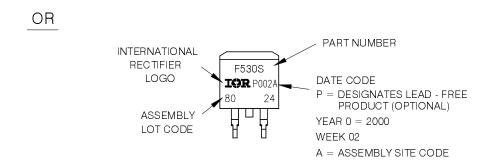
EXAMPLE: THIS IS AN IRF530S WITH

LOT CODE 8024

ASSEMBLED ON WW 02, 2000 IN THE ASSEMBLY LINE "L"

Note: "P" in assembly line position indicates "Lead — Free"

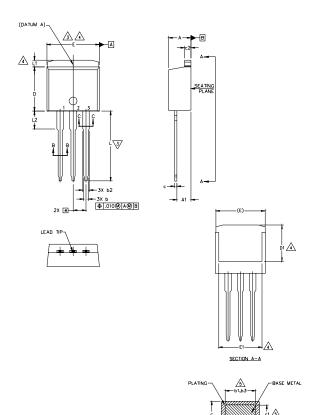




Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

TO-262 Package Outline

Dimensions are shown in millimeters (inches)



- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION b1 AND c1 APPLY TO BASE METAL ONLY.

6. CONTROLLING DIMENSION: INCH.

7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

S	DIMENSIONS						
M B O	MILLIM	ETERS	INC	HES	NOT ES		
L	MIN.	MAX.	MIN.	MAX,	E S		
Α	4.06	4.83	.160	.190			
A1	2.03	3.02	.080	.119			
b	0.51	0.99	.020	.039			
ь1	0.51	0.89	.020	.035	5		
b2	1,14	1.78	.045	.070			
ь3	1.14	1.73	.045	.068	5		
С	0.38	0.74	.015	.029			
c1	0.38	0.58	.015	.023	5		
c2	1.14	1.65	.045	.065			
D	8.38	9.65	.330	.380	3		
D1	6.86	-	.270	-	4		
E	9.65	10.67	.380	.420	3,4		
E1	6.22	-	.245		4		
e	2.54	BSC	,100 BSC				
L	13.46	14.10	.530	.555			
L1	-	1.65	-	.065	4		
L2	3.56	3,71	.140	,146			

LEAD ASSIGNMENTS

<u>HEXFET</u>

1.- GATE

2.- DRAIN 3.- SOURCE 4. - DRAIN

IGBTs, CoPACK

2.- COLLECTOR
3.- EMITTER
4.- COLLECTOR

TO-262 Part Marking Information

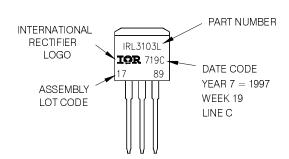
EXAMPLE: THIS IS AN IRL3103L

LOT CODE 1789

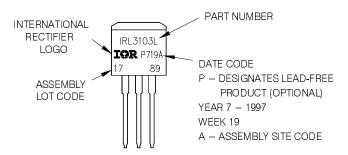
ASSEMBLED ON WW 19, 1997

IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead - Free"

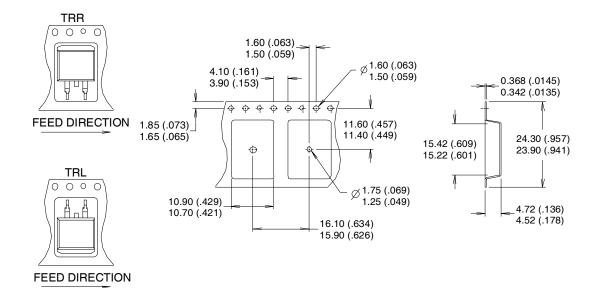


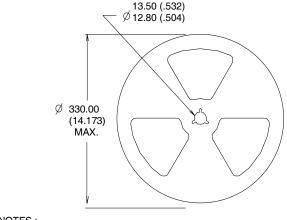
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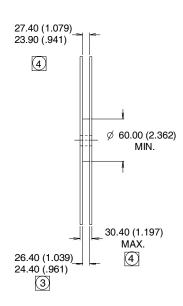


D²Pak (TO-263AB) Tape & Reel Information

Dimensions are shown in millimeters (inches)







NOTES:

- 1. COMFORMS TO EIA-418.
- CONTROLLING DIMENSION: MILLIMETER.
- 3 DIMENSION MEASURED @ HUB.
- 4 INCLUDES FLANGE DISTORTION @ OUTER EDGE.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market. Qualification Standards can be found on IR's Web site.



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TAC Fax: (310) 252-7903

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